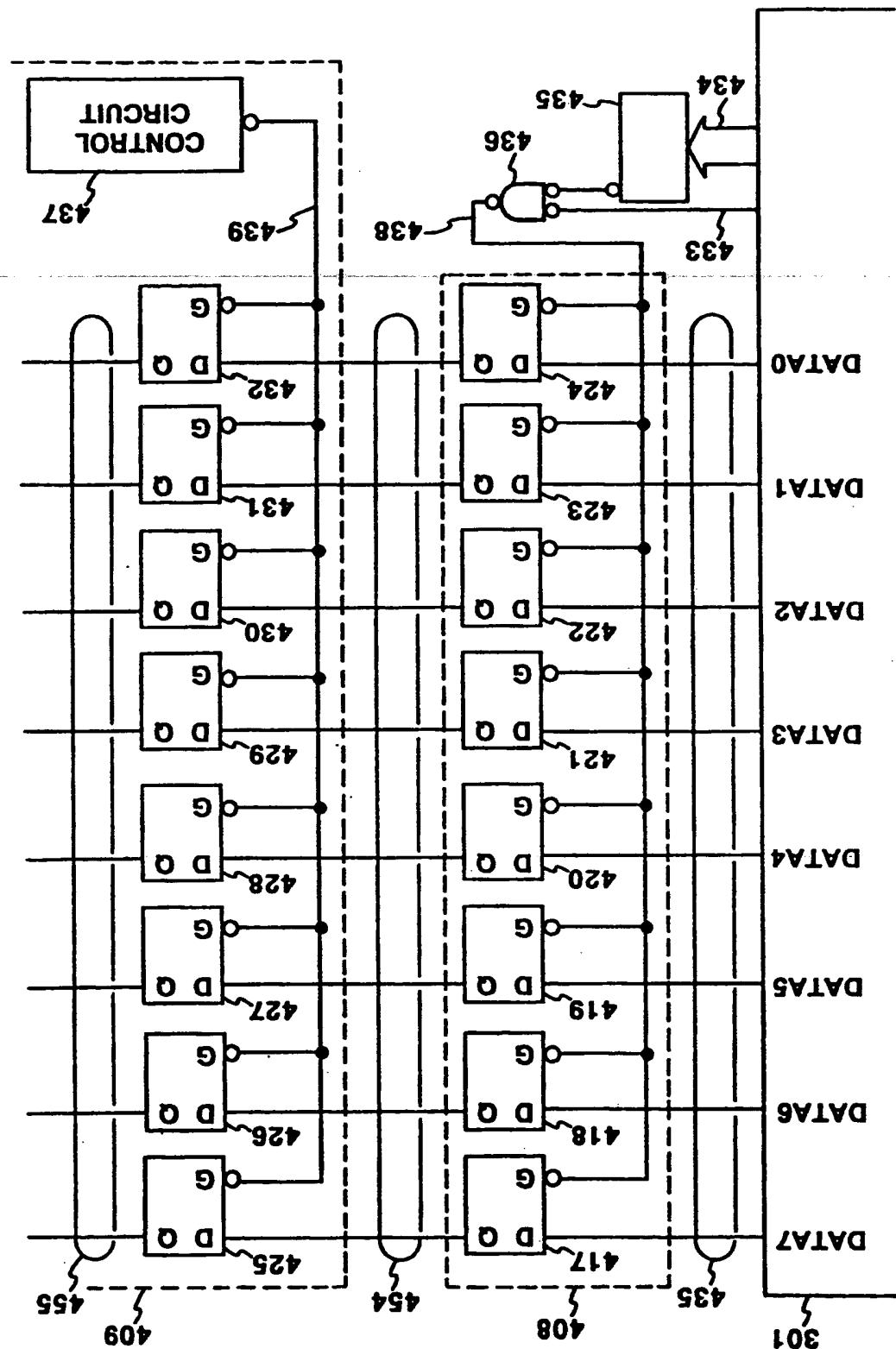


| | L # | Hits | Search Text | DBs |
|----|-----|--------|--|-------------------------------------|
| 1 | L1 | 14035 | (scatter\$3 gather\$3) near10 (bit byte element item) | USPAT; US-PGPUB |
| 2 | L3 | 5584 | (scatter\$3 gather\$3) near10 (bit byte element item) | EPO; JPO; DERWENT |
| 3 | L2 | 144 | 1 near20 mask\$3 | USPAT; US-PGPUB |
| 4 | L4 | 44 | 3 near20 mask\$3 | EPO; JPO; DERWENT; IBM_TDB |
| 5 | L6 | 2739 | (scatter\$3 gather\$3) near20 mask\$3 | USPAT; US-PGPUB |
| 6 | L10 | 47646 | (reorder\$3 order\$3 rearrang\$3 arang\$3) near10 (bit byte element item) | EPO; JPO; DERWENT; IBM_TDB |
| 7 | L11 | 1026 | (scatter\$3 gather\$3) near20 mask\$3 | EPO; JPO; DERWENT; IBM_TDB |
| 8 | L12 | 4 | 10 and 11 | EPO; JPO; DERWENT; IBM_TDB |
| 9 | L9 | 103 | (reorder\$3 order\$3 rearrang\$3 arang\$3 scatter\$3 gather\$3).ab,ti. and 7 | USPAT; US-PGPUB |
| 10 | L13 | 351267 | (reorder\$3 order\$3 rearrang\$3 arrang\$3) near10 (bit byte element item) | USPAT; US-PGPUB |
| 11 | L14 | 170489 | (reorder\$3 order\$3 rearrang\$3 arrang\$3) near10 (bit byte element item) | EPO; JPO; DERWENT; IBM_TDB |
| 12 | L16 | 593 | 6 and 13 | USPAT; US-PGPUB |
| 13 | L18 | 15 | 11 and 14 | EPO; JPO; DERWENT; IBM_TDB |
| 14 | L17 | 171 | (reorder\$3 order\$3 rearrang\$3 arrang\$3 scatter\$3 gather\$3).ab,ti. and 16 | USPAT; US-PGPUB |

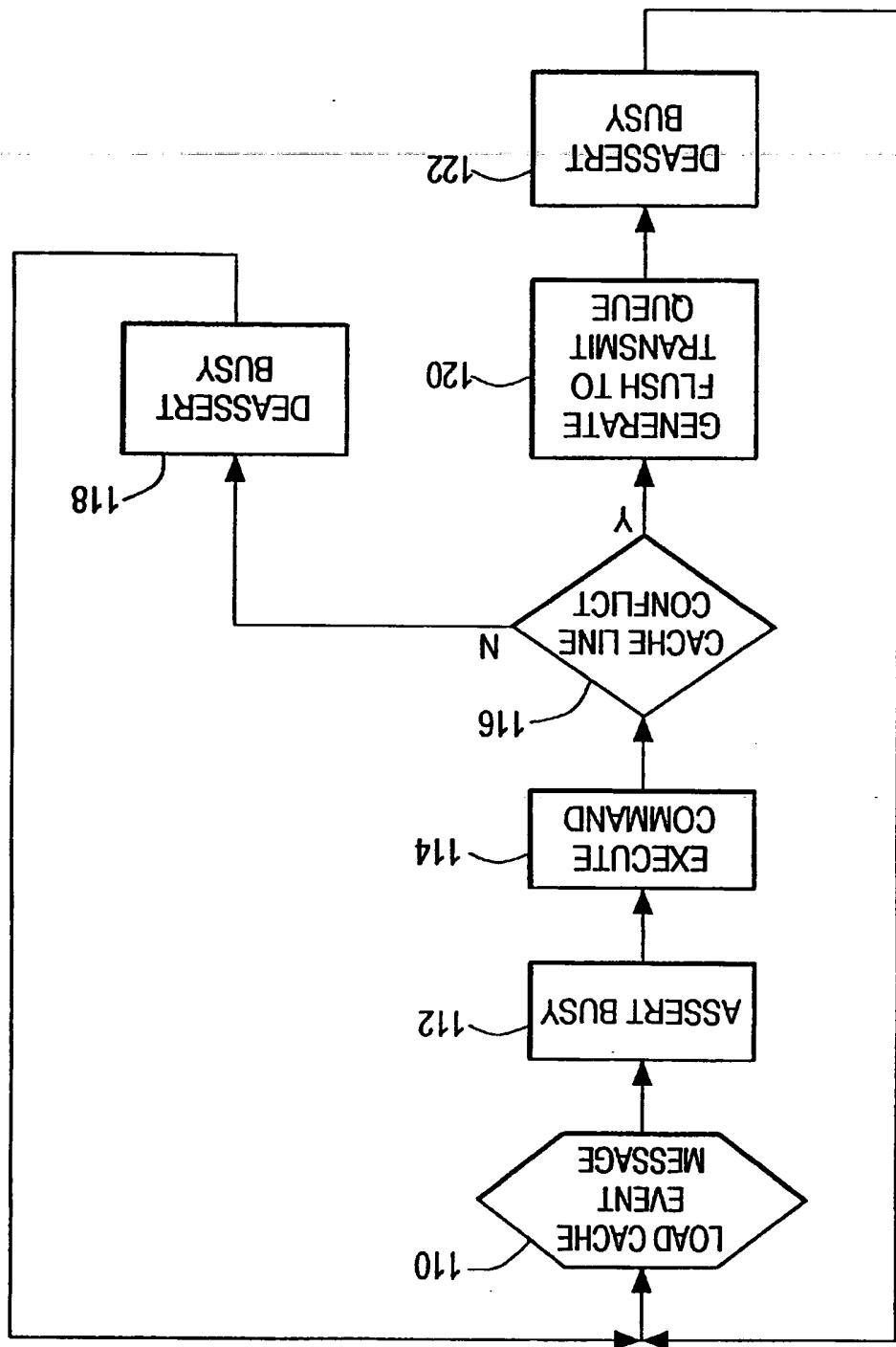
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FIG. 35 (PRIOR ART)



| | Document ID | U | Title | Current OR |
|----|------------------|-------------------------------------|---|------------|
| 1 | JP 20020 96461 A | <input type="checkbox"/> | DEVICE FOR IMAGE RECORDING, METHOD FOR CONTROLLING IMAGE RECORDING, AND RECORDING MEDIUM | |
| 2 | JP 10096 700 A | <input type="checkbox"/> | APPARATUS FOR INSPECTING FOREIGN MATTER | |
| 3 | JP 08201 313 A | <input type="checkbox"/> | DEFECT INSPECTION METHOD FOR TRANSPARENT PLATE-LIKE BODY AND DEVICE THEREOF | |
| 4 | JP 07198 625 A | <input type="checkbox"/> | PRINT INSPECTING SENSOR | |
| 5 | JP 05079 913 A | <input type="checkbox"/> | STRAY LIGHT FREE FOURIER SPECTROPHOTOMETER | |
| 6 | JP 05031 670 A | <input type="checkbox"/> | BLAST PROCESSING METHOD FOR METALLIC PRODUCT | |
| 7 | JP 04194 908 A | <input type="checkbox"/> | LIQUID CRYSTAL DISPLAY DEVICE | |
| 8 | JP 60024 568 A | <input type="checkbox"/> | COLOR TONER CONCENTRATION DETECTOR | |
| 9 | WO 96055 03 A1 | <input type="checkbox"/> | DEVICE FOR TESTING OPTICAL ELEMENTS | |
| 10 | US 58447 22 A | <input type="checkbox"/> | Polarization beam splitter for colour projection system - has wave blocking element arranged at bottom edge of mask and immersed in prismatic fluid, for minimizing scattering of incident electromagnetic wave | |
| 11 | JP 10096 700 A | <input checked="" type="checkbox"/> | Inspection apparatus for detecting adhesion of foreign particles in mask used in exposure system of semiconductor device, LCD element manufacture - has optical correction element arranged in between mask and optical receiving unit that receives reflected light, to correct aberrational defects | |
| 12 | JP 09257 685 A | <input checked="" type="checkbox"/> | Photodetector for measuring particle size distribution in specimen - includes mask on light receiving surface to focus scattered light into fixed area of light receiving element | |
| 13 | US 52989 69 A | <input checked="" type="checkbox"/> | Combined optical train for laser spectroscopy - has first focussing lens located one focal length from centre of sample cell, second focussing lens one focal length ahead of aperture element, and optical masking element between two lenses | |
| 14 | EP 55665 5 A | <input checked="" type="checkbox"/> | Grading and evaluating method for optical elements such as lenses - scanning rotated linear wedge shaped beam of white light on entire lens surface and detecting defect scattered light using CCD via mask | |
| 15 | US 45989 97 A | <input checked="" type="checkbox"/> | Detector for defects and dust on semiconductor wafer or video disc - detects scattered light free of diffracted beams from pattern by mask with apertures blocking specular reflections | |

FIG. 6



| | Document ID | U | Title | Current OR |
|----|---------------------|-------------------------------------|--|-------------|
| 1 | US 20040 07876 3 A1 | <input type="checkbox"/> | Short edge smoothing for enhanced scatter bar placement | 716/2 |
| 2 | US 20040 07505 3 A1 | <input checked="" type="checkbox"/> | Particle-optical arrangements and particle-optical systems | 250/310 |
| 3 | US 20040 07312 0 A1 | <input checked="" type="checkbox"/> | Systems and methods for spectroscopy of biological tissue | 600/478 |
| 4 | US 20040 05805 8 A1 | <input checked="" type="checkbox"/> | Raman-active taggants and thier recognition | 427/7 |
| 5 | US 20040 04701 4 A1 | <input checked="" type="checkbox"/> | In-line holographic mask for micromachining | 359/15 |
| 6 | US 20040 01194 8 A1 | <input checked="" type="checkbox"/> | High accuracy miniature grating encoder readhead using fiber optic receiver channels | 250/231 .13 |
| 7 | US 20040 00834 3 A1 | <input checked="" type="checkbox"/> | Electromagnetic radiation attenuating and scattering member with improved thermal stability | 356/243 .1 |
| 8 | US 20030 19139 8 A1 | <input checked="" type="checkbox"/> | Systems and methods for spectroscopy of biological tissue | 600/478 |
| 9 | US 20030 15553 2 A1 | <input checked="" type="checkbox"/> | Electron-beam lithography | 250/492 .3 |
| 10 | US 20030 11242 1 A1 | <input checked="" type="checkbox"/> | Apparatus and method of image enhancement through spatial filtering | 355/71 |
| 11 | US 20030 10376 0 A1 | <input checked="" type="checkbox"/> | OPTICAL ELEMENT HAVING PROGRAMMED OPTICAL STRUCTURES | 385/146 |
| 12 | US 20030 07752 1 A1 | <input checked="" type="checkbox"/> | Method for producing scatter lines in mask structures for fabricating integrated electrical circuits | 430/5 |
| 13 | US 20030 07658 3 A1 | <input checked="" type="checkbox"/> | Ultra-broadband UV microscope imaging system with wide range zoom capability | 359/357 |
| 14 | US 20030 07241 5 A1 | <input checked="" type="checkbox"/> | Method for producing a scattered radiation grid or collimator | 378/154 |
| 15 | US 20030 06473 4 A1 | <input checked="" type="checkbox"/> | Modified transmission method for improving accuracy for E-911 calls | 455/456 .1 |
| 16 | US 20030 05304 8 A1 | <input checked="" type="checkbox"/> | Electron microscope and spectroscopy system | 356/301 |
| 17 | US 20030 03080 2 A1 | <input checked="" type="checkbox"/> | MEASUREMENT OF PARTICLE SIZE DISTRIBUTION | 356/336 |

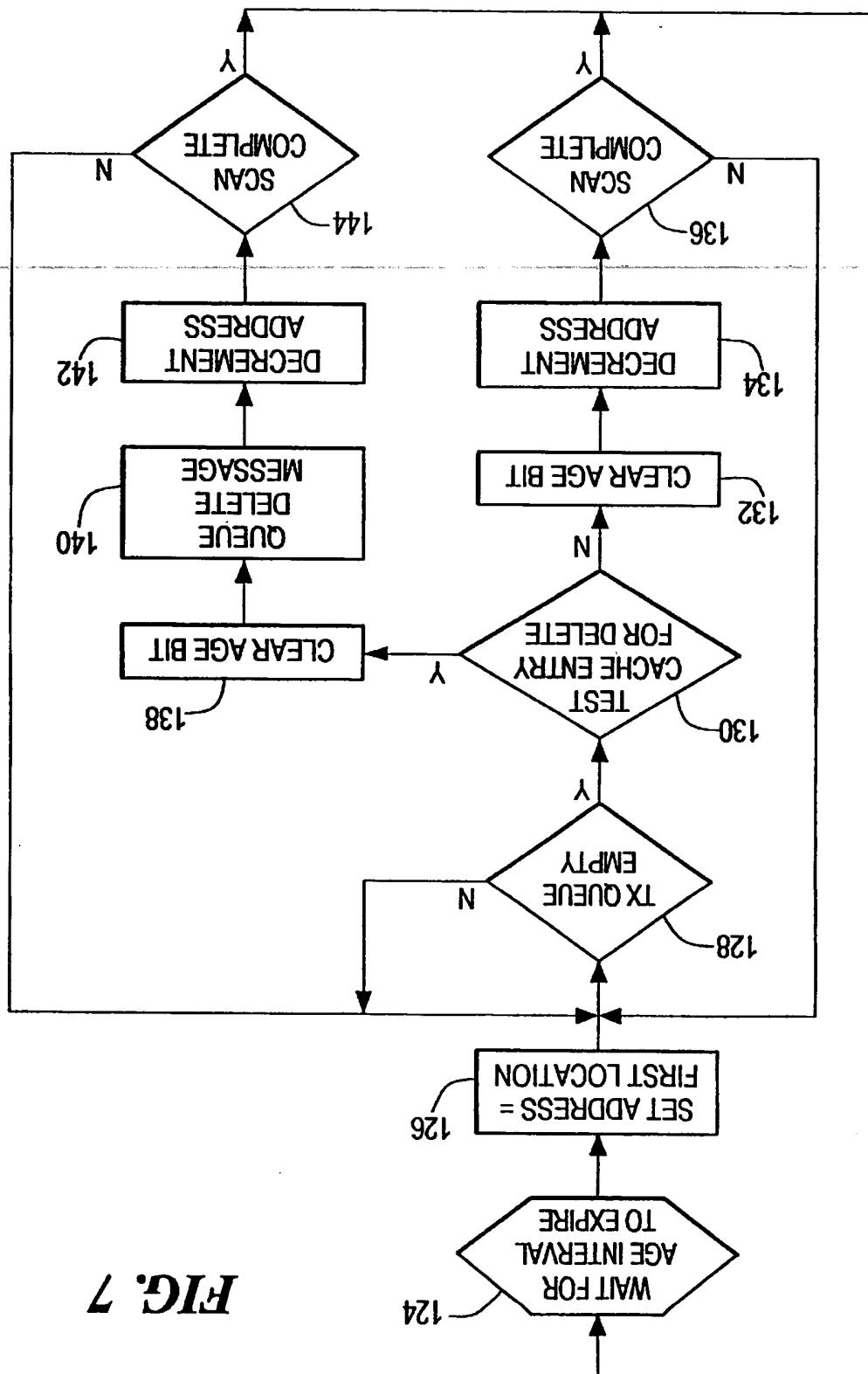


FIG. 7

| | Document ID | U | Title | Current OR |
|----|---------------------|-------------------------------------|--|-------------|
| 18 | US 20030 03078 3 A1 | <input checked="" type="checkbox"/> | Consumable tube for use with a flow cytometry-based hematology system | 356/39 |
| 19 | US 20030 03005 5 A1 | <input checked="" type="checkbox"/> | Color-filter substrate assembly, method for manufacturing the color-filter substrate assembly, electro-optical device, method for manufacturing electro-optical device, and electronic apparatus | 257/72 |
| 20 | US 20030 01951 8 A1 | <input checked="" type="checkbox"/> | Photovoltaic element and process for the production thereof | 136/256 |
| 21 | US 20030 01685 4 A1 | <input checked="" type="checkbox"/> | Radiation image processing apparatus, image processing system, radiation image processing method, storage medium, and program | 382/132 |
| 22 | US 20030 01172 2 A1 | <input checked="" type="checkbox"/> | Method of fabricating near-field light-generating element | 349/43 |
| 23 | US 20020 18252 3 A1 | <input checked="" type="checkbox"/> | Method for carrying out a rule-based optical proximity correction with simultaneous scatter bar insertion | 430/30 |
| 24 | US 20020 17183 1 A1 | <input checked="" type="checkbox"/> | Polarized light scattering spectroscopy of tissue | 356/369 |
| 25 | US 20020 16372 9 A1 | <input checked="" type="checkbox"/> | FIELD-OF-VIEW CONTROLLING ARRANGEMENTS | 359/613 |
| 26 | US 20020 16372 8 A1 | <input checked="" type="checkbox"/> | Optical sheets or overlays | 359/613 |
| 27 | US 20020 08527 1 A1 | <input checked="" type="checkbox"/> | Broad spectrum ultraviolet catadioptric imaging system | 359/359 |
| 28 | US 20020 05727 6 A1 | <input checked="" type="checkbox"/> | Data processing apparatus, processor and control method | 345/555 |
| 29 | US 20020 03920 9 A1 | <input checked="" type="checkbox"/> | IN-LINE HOLOGRAPHIC MASK FOR MICROMACHINING | 359/15 |
| 30 | US 20020 02549 0 A1 | <input checked="" type="checkbox"/> | Raman-active taggants and their recognition | 430/270 .15 |
| 31 | US 20020 02464 3 A1 | <input checked="" type="checkbox"/> | Projection exposure apparatus having aberration measurement device | 355/52 |
| 32 | US 20020 02145 1 A1 | <input checked="" type="checkbox"/> | Scanning interferometric near-field confocal microscopy with background amplitude reduction and compensation | 356/511 |
| 33 | US 20010 04687 0 A1 | <input checked="" type="checkbox"/> | Modified transmission method for improving accuracy for E-911 calls | 455/456 .2 |
| 34 | US 20010 02147 7 A1 | <input checked="" type="checkbox"/> | Method of manufacturing a device by means of a mask phase-shifting mask for use in said method | 430/5 |

BACKGROUND OF THE INVENTION

0 The invention is predicated in part upon recognition that
1 address certain operations are well suited to
2 examples, it addresses information for lowwattage data units is
3 the switch, the data unit and subsequent data units should
4 nevertheless reach the destination because flooding
5 will be employed. Further, the address information can be
6 learned from any subsequent data units transmitted by the
7 same source device. Hence, "strict coherence", where each
8 and every learning operation is implemented, is not required
9 for switch operation, and consistency may be obtained with
10 "weak coherence" by which some learning operations may
11 be dropped (not impeded). The invention is also predi-
12 cated in part upon recognition that address cache aging
13 operations are well suited to
14 not removed after the first aging interval during which it was
15 in remains unused. Hence, "weak coherence" is also
16 acceptable for aging operations.

In accordance with the present invention, in a network switch device in which a distributed address cache having a plurality of cache segments is employed, events initiated at address segments of the distributed address cache, such as cache segments of the distributed address cache, are centralized and concentrated in the cache segments in the distributed address cache. In order to maintain consistency throughout the distributed address cache, the cache segments in the distributed address cache are each updated by the cache segments in the distributed address cache, such as cache segments of the distributed address cache, are centralized and concentrated in the cache segments in the distributed address cache.

BRIEF SUMMARY OF THE INVENTION

Forwarding and aging operations. One technique is to provide each I/O ASIC with access to the address cache to support address lookups and aging operations. Another technique is to provide a centralized address cache. However, the use of a single, centralized address cache increases the task of increasing the number of ports in the switch because the memory bandwidth required to support address access increases as the number of ports increases.

In an effort to ensure that the address cache contains accurate address information for active data flows, unlinked entries in the address cache may be deleted in accordance with an “aging” technique. In particular, any entries that are not referenced in response to a source address search within a predetermined aging interval are deleted. 90

| Document ID | U | Title | Current OR |
|------------------------|-------------------------------------|--|------------|
| 35 US 20010 01640 4 A1 | <input checked="" type="checkbox"/> | GaN substrate including wide low - defect region for use in semiconductor element | 438/496 |
| 36 US 20010 01493 6 A1 | <input checked="" type="checkbox"/> | Data processing device, system, and method using a table | 711/221 |
| 37 US 67010 28 B1 | <input checked="" type="checkbox"/> | Method and apparatus for fast signal convolution using spline kernel | 382/279 |
| 38 US 66899 51 B2 | <input checked="" type="checkbox"/> | Photovoltaic element and process for the production thereof | 136/256 |
| 39 US 66895 45 B2 | <input checked="" type="checkbox"/> | Method of fabricating near-field light-generating element | 430/321 |
| 40 US 66861 38 B1 | <input checked="" type="checkbox"/> | Color motion picture print film with improved raw stock keeping | 430/505 |
| 41 US 66715 26 B1 | <input checked="" type="checkbox"/> | Probe and apparatus for determining concentration of light-absorbing materials in living tissue | 600/310 |
| 42 US 66678 09 B2 | <input checked="" type="checkbox"/> | Scanning interferometric near-field confocal microscopy with background amplitude reduction and compensation | 356/511 |
| 43 US 66467 42 B1 | <input checked="" type="checkbox"/> | Optical device and method for multi-angle laser light scatter | 356/342 |
| 44 US 66248 90 B2 | <input checked="" type="checkbox"/> | Polarized light scattering spectroscopy of tissue | 356/369 |
| 45 US 66181 74 B2 | <input checked="" type="checkbox"/> | In-line holographic mask for micromachining | 359/15 |
| 46 US 66103 51 B2 | <input checked="" type="checkbox"/> | Raman-active taggants and their recognition | 427/7 |
| 47 US 66097 99 B1 | <input checked="" type="checkbox"/> | Field-of-view controlling arrangements | 359/613 |
| 48 US 65446 94 B2 | <input checked="" type="checkbox"/> | Method of manufacturing a device by means of a mask phase-shifting mask for use in said method | 430/5 |
| 49 US 65206 49 B1 | <input checked="" type="checkbox"/> | Image projection device and associated method | 353/94 |
| 50 US 65194 65 B2 | <input checked="" type="checkbox"/> | Modified transmission method for improving accuracy for E-911 calls | 455/456 .1 |
| 51 US 65074 00 B1 | <input checked="" type="checkbox"/> | Optical system for multi-part differential particle discrimination and an apparatus using the same | 356/338 |
| 52 US 64983 51 B1 | <input checked="" type="checkbox"/> | Illumination system for shaping extreme ultraviolet radiation used in a lithographic projection apparatus | 250/492 .2 |
| 53 US 64905 30 B1 | <input checked="" type="checkbox"/> | Aerosol hazard characterization and early warning network | 702/24 |
| 54 US 64836 38 B1 | <input checked="" type="checkbox"/> | Ultra-broadband UV microscope imaging system with wide range zoom capability | 359/351 |
| 55 US 64769 10 B1 | <input checked="" type="checkbox"/> | Light scattering apparatus and method for determining radiation exposure to plastic detectors | 356/336 |
| 56 US 64632 90 B1 | <input checked="" type="checkbox"/> | Mobile-assisted network based techniques for improving accuracy of wireless location system | 455/456 .1 |

The arbiter device 42 is employed to manage the event sharing bus 20. When an event message is generated as a result of activity at an I/O ASIC, the event message is placed

ASICS[®]) 12, 14, 16, 18 that are interconnected via an event bus 20 and a switch fabric 22 such as a crosspoint ASIC. Each I/O ASIC includes a plurality of ports that are connected with other devices in the network. The ports are employed for receiving and transmitting data units. I/O ASICs may include different numbers of ports. For example, in the illustrated embodiment ASIC 18 includes 16 ports while ASICs 12, 14, 16 include 8 ports. Further, different I/O ASICs may support different transmission protocols and different data transmission rates. The switch 10 includes a distributed address cache having a plurality of separate cache segments 24, 26, 28, 30, each of which is coupled to a different I/O ASIC. In the illustrated embodiment, cache 24 is connected with I/O ASIC 14, cache 26 is connected with I/O ASIC 12, cache 28 is connected with I/O ASIC 16 and cache 30 is connected with I/O ASIC 18. Cache 22 is connected with I/O ASIC 11, cache 28 is connected with I/O ASIC 10 and cache 30 is connected with I/O ASIC 9. Cache 24 is connected with I/O ASIC 12, cache 26 is connected with I/O ASIC 14, cache 28 is connected with I/O ASIC 16 and cache 30 is connected with I/O ASIC 18.

FIG. 1 illustrates a switch **10** that facilitates movement of data units in a network. The switch **10** includes a plurality of input/output Applicaton Specific Integrated Circuits ("ASICs")

BRIEF DESCRIPTION OF THE SEVERAL VIEWS OF THE DRAWING

| Document ID | U | Title | Current OR |
|-------------------|-------------------------------------|---|-------------|
| 57 US 64490 23 B2 | <input checked="" type="checkbox"/> | Active matrix liquid crystal display device | 349/62 |
| 58 US 64479 59 B1 | <input checked="" type="checkbox"/> | Amplitude mask for writing long-period gratings | 430/5 |
| 59 US 64435 79 B1 | <input checked="" type="checkbox"/> | Field-of-view controlling arrangements | 359/613 |
| 60 US 64406 54 B1 | <input checked="" type="checkbox"/> | Photographic element containing an electrically-conductive layer | 430/529 |
| 61 US 64406 15 B1 | <input checked="" type="checkbox"/> | Method of repairing a mask with high electron scattering and low electron absorption properties | 430/5 |
| 62 US 64373 53 B1 | <input checked="" type="checkbox"/> | Particle-optical apparatus and process for the particle-optical production of microstructures | 250/492 .23 |
| 63 US 64207 14 B1 | <input checked="" type="checkbox"/> | Electron beam imaging apparatus | 250/396 ML |
| 64 US 64080 49 B1 | <input checked="" type="checkbox"/> | Apparatus, methods, and computer programs for estimating and correcting scatter in digital radiographic and tomographic imaging | 378/98. 12 |
| 65 US 63777 26 B1 | <input checked="" type="checkbox"/> | Transverse mode transformer | 385/28 |
| 66 US 63625 15 B1 | <input checked="" type="checkbox"/> | GaN substrate including wide low-defect region for use in semiconductor element | 257/639 |
| 67 US 63340 59 B1 | <input checked="" type="checkbox"/> | Modified transmission method for improving accuracy for e-911 calls | 455/404 .2 |
| 68 US 63231 02 B1 | <input checked="" type="checkbox"/> | Method of manufacturing a semiconductor device | 438/424 |
| 69 US 63134 67 B1 | <input checked="" type="checkbox"/> | Broad spectrum ultraviolet inspection methods employing catadioptric imaging | 250/372 |
| 70 US 63046 26 B1 | <input checked="" type="checkbox"/> | Two-dimensional array type of X-ray detector and computerized tomography apparatus | 378/19 |
| 71 US 62951 20 B1 | <input checked="" type="checkbox"/> | Position detection technique applied to proximity exposure | 355/53 |
| 72 US 62854 39 B1 | <input checked="" type="checkbox"/> | Position detection technique applied to proximity exposure | 355/53 |
| 73 US 62485 10 B1 | <input checked="" type="checkbox"/> | Motion picture intermediate film with process surviving antistatic backing layer | 430/396 |
| 74 US 62464 51 B1 | <input checked="" type="checkbox"/> | Stereoscopic image displaying method and stereoscopic image apparatus | 349/15 |
| 75 US 62330 56 B1 | <input checked="" type="checkbox"/> | Interferometric at-wavelength flare characterization of EUV optical systems | 356/520 |
| 76 US 62330 43 B1 | <input checked="" type="checkbox"/> | Position detection technique applied to proximity exposure | 355/53 |
| 77 US 61779 94 B1 | <input checked="" type="checkbox"/> | Relating to the measurement of particle size distribution | 356/343 |
| 78 US 61772 37 B1 | <input checked="" type="checkbox"/> | High resolution anti-scatter x-ray grid and laser fabrication method | 430/320 |
| 79 US 61335 76 A | <input checked="" type="checkbox"/> | Broad spectrum ultraviolet inspection methods employing catadioptric imaging | 250/461 .1 |

| Document ID | U | Title | Current OR |
|-------------------|-------------------------------------|--|-------------|
| 80 US 61181 59 A | <input checked="" type="checkbox"/> | Electrically programmable memory cell configuration | 257/390 |
| 81 US 61153 44 A | <input checked="" type="checkbox"/> | Device and method for optical data storage having multiple optical states | 369/100 |
| 82 US 61009 78 A | <input checked="" type="checkbox"/> | Dual-domain point diffraction interferometer | 356/498 |
| 83 US 61009 71 A | <input checked="" type="checkbox"/> | Surface inspection tool | 356/237 .2 |
| 84 US 60493 73 A | <input checked="" type="checkbox"/> | Position detection technique applied to proximity exposure | 355/53 |
| 85 US 60347 76 A | <input checked="" type="checkbox"/> | Microroughness-blind optical scattering instrument | 356/369 |
| 86 US 60159 76 A | <input checked="" type="checkbox"/> | Fabrication apparatus employing energy beam | 250/492 .23 |
| 87 US 60059 16 A | <input checked="" type="checkbox"/> | Apparatus and method for imaging with wavefields using inverse scattering techniques | 378/87 |
| 88 US 59993 10 A | <input checked="" type="checkbox"/> | Ultra-broadband UV microscope imaging system with wide range zoom capability | 359/351 |
| 89 US 59662 16 A | <input checked="" type="checkbox"/> | On-axis mask and wafer alignment system | 356/401 |
| 90 US 59561 74 A | <input checked="" type="checkbox"/> | Broad spectrum ultraviolet catadioptric imaging system | 359/357 |
| 91 US 59521 65 A | <input checked="" type="checkbox"/> | Topcoat for motion picture film | 430/510 |
| 92 US 59404 68 A | <input checked="" type="checkbox"/> | Coded aperture X-ray imaging system | 378/57 |
| 93 US 59332 30 A | <input checked="" type="checkbox"/> | Surface inspection tool | 356/237 .2 |
| 94 US 59239 09 A | <input checked="" type="checkbox"/> | Distance measuring device and a camera using the same | 396/114 |
| 95 US 59103 99 A | <input checked="" type="checkbox"/> | Backing layer for motion picture film | 430/517 |
| 96 US 58895 80 A | <input checked="" type="checkbox"/> | Scanning-slit exposure device | 355/67 |
| 97 US 58741 77 A | <input checked="" type="checkbox"/> | Strut aligning fixture | 428/596 |
| 98 US 58689 52 A | <input checked="" type="checkbox"/> | Fabrication method with energy beam | 216/66 |
| 99 US 58300 64 A | <input checked="" type="checkbox"/> | Apparatus and method for distinguishing events which collectively exceed chance expectations and thereby controlling an output | 463/22 |
| 100 US 58074 48 A | <input checked="" type="checkbox"/> | Solid object generation | 156/58 |
| 101 US 57988 27 A | <input checked="" type="checkbox"/> | Apparatus and method for determination of individual red blood cell shape | 356/39 |
| 102 US 57891 19 A | <input checked="" type="checkbox"/> | Image transfer mask for charged particle-beam | 430/5 |

| Document ID | U | Title | Current OR |
|-------------------|-------------------------------------|--|-------------|
| 103 US 57861 34 A | <input checked="" type="checkbox"/> | Motion picture print film | 430/517 |
| 104 US 57841 60 A | <input checked="" type="checkbox"/> | Non-contact interferometric sizing of stochastic particles | 356/496 |
| 105 US 57708 63 A | <input checked="" type="checkbox"/> | Charged particle beam projection apparatus | 250/492 .2 |
| 106 US 57472 32 A | <input checked="" type="checkbox"/> | Motion imaging film comprising a carbon black-containing backing and a process surviving conductive subbing layer | 430/514 |
| 107 US 57436 12 A | <input checked="" type="checkbox"/> | Liquid crystal projector | 353/97 |
| 108 US 57175 18 A | <input checked="" type="checkbox"/> | Broad spectrum ultraviolet catadioptric imaging system | 359/357 |
| 109 US 57126 85 A | <input checked="" type="checkbox"/> | Device to enhance imaging resolution | 348/360 |
| 110 US 56795 05 A | <input checked="" type="checkbox"/> | Photographic element useful as a motion picture print film | 430/523 |
| 111 US 56506 31 A | <input checked="" type="checkbox"/> | Electron beam writing system | 250/492 .2 |
| 112 US 56400 13 A | <input checked="" type="checkbox"/> | Infrared sensor having a heat sensitive semiconductor portion that detects and absorbs infrared rays | 250/338 .4 |
| 113 US 56019 67 A | <input checked="" type="checkbox"/> | Blue sensitized tabular emulsions for inverted record order film | 430/505 |
| 114 US 55944 78 A | <input checked="" type="checkbox"/> | Ink jet recording apparatus for divisionally driving a recording head with a plurality of ink jet orifices grouped into blocks | 347/41 |
| 115 US 55880 32 A | <input checked="" type="checkbox"/> | Apparatus and method for imaging with wavefields using inverse scattering techniques | 378/8 |
| 116 US 55878 19 A | <input checked="" type="checkbox"/> | Display device | 349/106 |
| 117 US 55439 12 A | <input checked="" type="checkbox"/> | Reflectometry of an optical waveguide using a low coherence reflectometer | 356/73.1 |
| 118 US 55395 14 A | <input checked="" type="checkbox"/> | Foreign particle inspection apparatus and method with front and back illumination | 356/237 .4 |
| 119 US 55348 68 A | <input checked="" type="checkbox"/> | Method and system for the detection and measurement of air phenomena and transmitter and receiver for use in the system | 342/26 |
| 120 US 55176 60 A | <input checked="" type="checkbox"/> | Read-write buffer for gathering write requests and resolving read conflicts based on a generated byte mask code | 711/117 |
| 121 US 54716 28 A | <input checked="" type="checkbox"/> | Multi-function permutation switch for rotating and manipulating an order of bits of an input data byte in either cyclic or non-cyclic mode | 712/223 |
| 122 US 54691 76 A | <input checked="" type="checkbox"/> | Focused array radar | 342/375 |
| 123 US 54628 37 A | <input checked="" type="checkbox"/> | Method of fabricating high density printed circuit board | 430/311 |
| 124 US 54480 75 A | <input checked="" type="checkbox"/> | Electron-beam exposure system having an improved rate of exposure throughput | 250/492 .22 |
| 125 US 54384 08 A | <input checked="" type="checkbox"/> | Measuring device and method for the determination of particle size distributions by scattered light measurements | 356/336 |

| | Document ID | U | Title | Current OR |
|-----|--------------|-------------------------------------|--|------------|
| 126 | US 5438405 A | <input checked="" type="checkbox"/> | Device and method for testing optical elements | 356/239.2 |
| 127 | US 5382773 A | <input checked="" type="checkbox"/> | Apparatus and method for fabricating a perforated web by light | 219/121.7 |
| 128 | US 5353133 A | <input checked="" type="checkbox"/> | A display having a standard or reversed schieren microprojector at each picture element | 349/5 |
| 129 | US 5331446 A | <input checked="" type="checkbox"/> | Liquid crystal optical element and a laser projection apparatus using polymer dispersed liquid crystal | 349/5 |
| 130 | US 5319481 A | <input checked="" type="checkbox"/> | Encapsulated liquid crystal optical read/write storage medium and system | 349/171 |
| 131 | US 5298969 A | <input checked="" type="checkbox"/> | Combined optical train for laser spectroscopy | 356/340 |
| 132 | US 5298968 A | <input checked="" type="checkbox"/> | Combined optical train for laser spectroscopy | 356/338 |
| 133 | US 5274420 A | <input checked="" type="checkbox"/> | Beamsplitter type lens elements with pupil-plane stops for lithographic systems | 355/67 |
| 134 | US 5224214 A | <input checked="" type="checkbox"/> | BuIffet for gathering write requests and resolving read conflicts by matching read and write requests | 710/39 |
| 135 | US 5162645 A | <input checked="" type="checkbox"/> | Photographic scanner with reduced susceptibility to scattering | 250/208.1 |
| 136 | US 5098181 A | <input checked="" type="checkbox"/> | Ophthalmic measuring apparatus | 351/221 |
| 137 | US 5066997 A | <input checked="" type="checkbox"/> | Semiconductor device | 257/211 |
| 138 | US 5046847 A | <input checked="" type="checkbox"/> | Method for detecting foreign matter and device for realizing same | 356/338 |
| 139 | US 5040020 A | <input checked="" type="checkbox"/> | Self-aligned, high resolution resonant dielectric lithography | 355/53 |
| 140 | US 5039907 A | <input checked="" type="checkbox"/> | Sparkle-free color display | 313/478 |
| 141 | US 5028135 A | <input checked="" type="checkbox"/> | Combined high spatial resolution and high total intensity selection optical train for laser spectroscopy | 356/340 |
| 142 | US 4988184 A | <input checked="" type="checkbox"/> | Ophthalmic disease detection apparatus | 351/221 |
| 143 | US 4922308 A | <input checked="" type="checkbox"/> | Method of and apparatus for detecting foreign substance | 356/237.4 |
| 144 | US 4898804 A | <input checked="" type="checkbox"/> | Self-aligned, high resolution resonant dielectric lithography | 430/311 |
| 145 | US 4856897 A | <input checked="" type="checkbox"/> | Raman spectrometer having Hadamard electrooptical mask and diode detector | 356/301 |
| 146 | US 4828385 A | <input checked="" type="checkbox"/> | Autolensmeter | 356/125 |
| 147 | US 4821304 A | <input checked="" type="checkbox"/> | Detection methods and apparatus for non-destructive inspection of materials with radiation | 378/86 |
| 148 | US 4764776 A | <input checked="" type="checkbox"/> | Thermo transfer printer | 347/232 |

| | Document | Pages | Printed | Missed | Copies |
|-------------|----------|-------|---------|--------|--------|
| US005628005 | 17 | 17 | 0 | 1 | |
| US005689639 | 13 | 13 | 0 | 1 | |
| US005712964 | 111 | 111 | 0 | 1 | |
| US006141344 | 12 | 12 | 0 | 1 | |
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| 149 US 46783 25 A | <input checked="" type="checkbox"/> | Apparatus for measuring optical properties of paper | 356/73 |
| 150 US 46680 89 A | <input checked="" type="checkbox"/> | Exposure apparatus and method of aligning exposure mask with workpiece | 356/139 .07 |
| 151 US 46424 71 A | <input checked="" type="checkbox"/> | Scattered radiation smoke detector | 250/574 |
| 152 US 46105 41 A | <input checked="" type="checkbox"/> | Foreign substance inspecting apparatus | 356/239 .8 |
| 153 US 45989 97 A | <input checked="" type="checkbox"/> | Apparatus and method for detecting defects and dust on a patterned surface | 356/237 .5 |
| 154 US 44958 17 A | <input checked="" type="checkbox"/> | Ultrasonic imaging device | 73/624 |
| 155 US 44822 14 A | <input checked="" type="checkbox"/> | Device for applying light to a linear array of magneto-optical light switches, notably for optical printers | 359/281 |
| 156 US 44213 91 A | <input checked="" type="checkbox"/> | Auto eye-refractometer | 351/211 |
| 157 US 43558 97 A | <input checked="" type="checkbox"/> | Near-simultaneous measurements at forward and back scatter angles in light scattering photometers | 356/338 |
| 158 US 43259 10 A | <input checked="" type="checkbox"/> | Automated multiple-purpose chemical-analysis apparatus | 422/64 |
| 159 US 43242 58 A | <input checked="" type="checkbox"/> | Ultrasonic doppler flowmeters | 600/455 |
| 160 US 42265 33 A | <input checked="" type="checkbox"/> | Optical particle detector | 356/338 |
| 161 US 41737 57 A | <input checked="" type="checkbox"/> | Liquid crystal display device | 345/50 |
| 162 US 41013 83 A | <input checked="" type="checkbox"/> | Process for testing microparticle response to its environment | 435/5 |
| 163 US 40700 98 A | <input checked="" type="checkbox"/> | Fisheye projection lens system for 35mm motion pictures | 359/725 |
| 164 US 40506 38 A | <input checked="" type="checkbox"/> | Radioactive matter containing waste gas treating installation | 241/222 |
| 165 US 39725 98 A | <input checked="" type="checkbox"/> | Multifaceted mirror structure for infrared radiation detector | 359/853 |
| 166 US 39281 40 A | <input checked="" type="checkbox"/> | Apparatus and process for testing microparticle response to its environment | 435/32 |
| 167 US 38389 08 A | <input checked="" type="checkbox"/> | GUIDED LIGHT STRUCTURES EMPLOYING LIQUID CRYSTAL | 349/19 |
| 168 US 37604 71 A | <input checked="" type="checkbox"/> | METHOD OF MAKING AN ELECTROMECHANICAL FILTER | 29/25.3 5 |
| 169 US 37448 78 A | <input checked="" type="checkbox"/> | LIQUID CRYSTAL MATRIX WITH CONTRAST ENHANCEMENT | 349/177 |
| 170 US 37137 43 A | <input checked="" type="checkbox"/> | FORWARD SCATTER OPTICAL TURBIDIMETER APPARATUS | 356/338 |
| 171 US 36472 79 A | <input type="checkbox"/> | COLOR DISPLAY DEVICES | 349/23 |

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